

Process Change Notice #1007201

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PCN Date: 20Jul10				Effective Date: 200ct10				
Title: C8051F70x/71x Revision C - Performance Improvement								
Originator: Sean Zeng		Phone: 512-532-5947			Dept: EMS			
Customer Contact: Kathy Haggar		Phone: 512-532-5261		5261	Dept: Sales			
PCN Type:								
☐ Assembly ☐ Di	sconti	nuance		Package	e 🗌 Test			
☐ Datasheet ☐ Fa	bricat	ication 🔀 Product Revision						
☐ Packing ☐ La	abeling			Locatio	n 🗌 Other			
Last Order Date: XXOct10								
PCN Details								
Description of Change:								
Silicon Laboratories (Silicon Labs) is pleased to announce the C8051F70x/F71x Rev C family of capacitive sensing MCUs now support six additional sensing channels and 2kv ESD protection (HBM) for all family members. C8051F70x/F71x Rev C also includes two new packages, QFN24 and QFN32, for small form factor products such as cell phones.								
Reason for Change:								
Added 6 sensing channels to enable customers to use the same capacitive sensing MCU to support a larger touch screen, more touch buttons or sliders. Eliminated all known errata. Improved ESD protection to 2kv in HBM. Also, expanded package options to include QFN 24 and QFN32.								
Impact on Form, Fit, Function, Quality, Reliability:								
C8051F70x/F71x Rev C form has been expanded by adding 6 additional capacitive sensing channels, and additional control of the capacitive to digital converter. All new functions are set by default to the configuration of Rev A to maintain 100% functional compatibility to Rev A.								
C8051F70x/F71x Rev C has improved ESD protection to 2kv HBM.								
C8051F70x/F71x Rev C is a pin compatible, drop-in replacement for the C8051F70x/F71x Rev A device.								

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Product Identification:

This PCN applies to devices ordered using the following ordering part numbers

Affected Ordering Part Numbers								
C8051F700-GQ	C8051F705-GM	C8051F708-GQ	C8051F713-GM					
C8051F700-GQR	C8051F705-GMR	C8051F708-GQR	C8051F713-GMR					
C8051F701-GQ	C8051F705-GQ	C8051F709-GQ	C8051F713-GQ					
C8051F701-GQR	C8051F705-GQR	C8051F709-GQR	C8051F713-GQR					
C8051F702-GQ	C8051F706-GM	C8051F710-GQ	C8051F714-GM					
C8051F702-GQR	C8051F706-GMR	C8051F710-GQR	C8051F714-GMR					
C8051F703-GQ	C8051F706-GQ	C8051F711-GQ	C8051F714-GQ					
C8051F703-GQR	C8051F706-GQR	C8051F711-GQR	C8051F714-GQR					
C8051F704-GM	C8051F707-GM	C8051F712-GM	C8051F715-GM					
C8051F704-GMR	C8051F707-GMR	C8051F712-GMR	C8051F715-GMR					
C8051F704-GQ	C8051F707-GQ	C8051F712-GQ	C8051F715-GQ					
C8051F704-GQR	C8051F707-GQR	C8051F712-GQR	C8051F715-GQR					

Note: Affected Part Numbers also include all custom parts made from the above listed base parts

Last Date of Unchanged Product: 200ct10

Subsequent to the Effective Date of this PCN, Silicon Labs will supply the new rev C parts for all C8051F70x/71x orders. The ordering part numbers have not changed subsequent to this product improvement.

Qualification Samples:

Samples are available now. Please contact your local Silicon Laboratories sales representative to order samples. A list of authorized sales representatives may be found at www.silabs.com

Customer Early Acceptance Sign Off:

Customers may approve early PCN acceptance by completing the information below:

Early Acceptance Date:

Name:

Company:

Email your early Acceptance approval to: katherine.haggar@silabs.com

Qualification Data: See Appendix A for the Qualification Report

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Appendix A: Qualification Report

C8051F70x/1x Qualification Report



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C8051F70x/1x Rev C, GSMC Fabrication, SPIL Assembly unless noted											
			Lot ID or	Fail/Pass							
TEST NAME	TEST CONDITION	QUALIFICATION	Start	or End	Summary	Status					
Die Qualification Tests											
High Temp Operating	JA108		Q26492	0/81							
Life	125°C, Dynamic	3 lots, N=>77	Q27958	0/84	0/245	Pass					
	Vcc=3.3V for 1000 hours		Q27422	0/80							
Low Temp Operating	JA108										
Life	-10°C, Dynamic	1 lot, N=>32	Q26491	0/41	0/41	Pass					
	Vcc=3.3V for 1000 hours										
ELFR	JA108		Q26724	0/527							
	125°C, Dynamic	3 lots, N>=500	Q27928	0/520	0/1556	Pass					
	Vcc=3.3V for 48 hours		Q27396	0/509							
ESD: Human Body	JA114	1 lot / 3 devices	Q28477	0/3	2000 V	Pass					
Model											
ESD: Machine Model	JA115	1 lot / 3 devices	Q28475	0/3	175 V	Pass					
ESD: Charged Device	JC101	1 lot / 3 devices	Q28476	0/3	2000 V	Pass					
Model											
Latch-up	JESD78, ±200mA	1 lot / 6 devices	Q28494	0/6	25 °C	Pass					
			Q28493	0/6	85 °C						
High Temperature Data	JESD22-A117		Q26661	0/40							
Retention / Cycling	85°C for 500 hours	3 lots, N>=39	Q27727	0/40	0/120	Pass					
Endurance for NVM			Q28548	0/40							
Low Temperature Data	JESD22-A108		Q26662	0/40							
Retention / Cycling	25°C for 500 hours	3 lots, N>=38	Q27728	0/40	0/120	Pass					
Endurance for NVM			Q28549	0/40							
Package Qualification Te	ests										

Notes: